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IC Tester Using MATLAB

Kiruthika K[1], Bhumika K Ramesh[2], Vishal G[3], Vivek N[4], Jyoti[5]
[1]Assistant Professor, Rajarajeswari College of Engineering, Ramohalli Cross, Banglore, 560074, India.
[2,3,4,5]UG Student, Rajarajeswari College of Engineering, Ramohalli Cross, Banglore, 560074, India.
Emails: *kiruthi.km21@gmail.com[1], bhumikaramesh2017@gmail.com[2], vishalgovindaraju@gmail.com[3], viveknag292003@gmail.com[4], jyotimature5@gmail.com[5]*

Abstract
Digital IC tester is a microcontroller grounded circuitry that tests rainfall the IC is in good working condition or bad condition. In diligence, testing of the product is a major and precious and time-consuming process. Before making the whole system work, testing is mandatorily performed to avoid crimes and uninvited results. also, in educational institutions, while performing practical it's necessary to check the ICs whether it's good or bad before performing trials. numerous a small fault at IC position makes system perform incorrectly and produce wrong labors. The proposed system gives a cheap, small, movable and easy to handle IC tester that tests the ICs belonging to introductory gate circuitry similar as mux, demux, encoder, introductory gates. A new system for the high- speed test and characterization of digital intertwined circuit prototypes has been developed. It utilizes a especially developed off- chip processor and supporting circuitry that's to be included on the prototype chip to grease the test and characterization process. The processor administers the stoner-defined test, receives and stores the test results. The test procedure and data is downloaded to the processor's memory through a standard interface. The supporting circuitry receives the test data serially from the processor, applies it to the named circuit within the IC, collects and reformat the test results and shoot it to the processor. It also includes a high- frequence configurable timepiece creator to be used for performance characterization of the prototyped circuits.
Keywords: *Digital IC tester; Microcontroller-based circuit testing; Fault detection*

1. Introduction
Numerous university experimenters and chip contrivers in small companies are faced with a delicate problem when it comes to developing new circuit intellectual products (IPs), the cost of prototyping. To corroborate their IP(s) they need to fabricate a prototype, test it and characterize its performance. With the current pets of over to many Giga Hertz, these circuits would bear veritably precious testers and reaches. The high cost of similar testing accoutrements is prohibitive for most universities. At the same time, trends in electronic design have gathered to what's known as an IP-Grounded design. This is a design methodology grounded once-using circuit blocks, videlicet the IP blocks. These blocks are designed and vindicated (through prototyping and testing) by IP merchandisers and are also used Andre-used by ASIC (operation-specific integrated circuits) and SoC (system on chip) contrivers. Hence, developing a cost-effective system for testing and characterizing prototypes of circuit IPs is largely desirable. The IC tester simply determines which are workable gates and which are defective. The main purpose of the design is to develop a digital IC tester that's veritably less precious and handy than that of what is available in requests. The end is to check the ICs in veritably due course of time and display results of ICs being good or defective incontinently. The necessary input signal conditions are applied to the inputs of the gate through microcontroller and affair of each gate is covered and compared with the verity table, and depending on that comparison IC is tested whether it's good or defective. The introductory function of digital IC tester is to test the sense functioning of the ICs as described in the verity table/ function table. The verity tables are stored in database while rendering of the microcontroller. The test displays the good ICs and defective ICs on TV. The test is being

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filled with the ICs belonging to the introductory sense gate IC series. There are numerous IC testers available on request, but we've developed a tester that's veritably cheap, movable, and easy to handle as well. Figure 1 shows Circuit Diagram. [1-5]

2. Objectives

1. Develop a Flexible IC Testing Platform: Create a versatile system that can accommodate various IC types and test requirements.
2. Implement Comprehensive Signal Generation and Data Acquisition: Design algorithms for generating test stimuli and capturing IC responses.
3. Perform Advanced Data Analysis and Fault Detection: Develop algorithms to process the acquired data, analyze IC performance, and identify faults.
4. Provide Intuitive User Interface and Visualization Tools: Design a user-friendly GUI for configuring tests, monitoring progress, and displaying results.
5. Integrate with Arduino Uno for Hardware Interface: Leverage the Arduino Uno as a cost-effective hardware bridge between MATLAB and the IC under test
6. Ensure Adaptability and Extensibility: Create a system that can be easily modified and expanded to support new IC types or testing requirements.
7. Optimize Testing Speed and Accuracy: Balance the performance capabilities of MATLAB with the demands of high-speed IC testing.
8. Enable Automated Testing and Data Logging: Implement scripted test sequences and data storage for efficient, repeatable testing.
9. Leverage MATLAB's Strengths in Signal Processing and Visualization: Utilize MATLAB's robust signal processing tools and visualization capabilities to enhance the tester's analytical abilities
10. Maintain Educational and Research Relevance: Design the tester in a way that makes it suitable for both educational and professional applications

3. Circuit Diagram

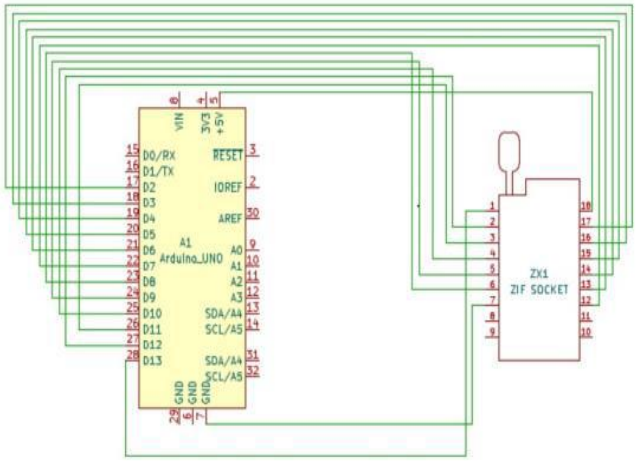

Figure 1 Circuit Diagram

Testing of digital electronic systems generally involves applying a set of test stimuli to inputs of the device-under-test (DUT) and analyzing responses of the system using a response analyzer. If the DUT generates correct output responses (also called the golden response) for all the input stimuli, the DUT is regarded as fault-free. Those DUTs that fail to meet the golden response are regarded as faulty or defective. This project describes a digital IC tester for testing 74xx series digital ICs using a MATLAB graphical user interface (GUI) drop-down menu based approach. MATLAB acts as the test stimuli generator to the IC, which is the DUT. The GUI initiates communication with the Arduino and provides a user-friendly and interactive approach to conduct the test. The MATLAB source program acts as the response analyzer and displays test results on the front panel of the GUI. As mentioned earlier, MATLAB is used to apply stimuli to the DUT (74xx series digital ICs) and also record the response of the DUT to stimuli. It then compares the response of the DUT with the correct/golden response to test whether the device is faulty or not. For a digital IC, the correct response is given in the form of a truth table. Acting as a response analyzer, the MATLAB verifies each and every possible outcome according to the truth table of a particular IC.74xx series ICs that can be tested by this project are 7400, 7402, 7404, 7408, 7432 and 7486. Truth tables for these ICs are shown on the next page. [6-10]

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4. Methodology

The development of an IC tester using MATLAB involves a structured approach that begins with a thorough requirement analysis to define the testing objectives and identify the necessary hardware and software tools. MATLAB is then used to create detailed behavioral models of the IC, allowing for initial test script development and simulation. The automation of test pattern generation based on the IC's specifications is a crucial step, enhancing the efficiency of the testing process. Integration with test equipment enables MATLAB to control the hardware and acquire data in real-time, enabling dynamic adjustment of parameters. During test execution, MATLAB systematically logs the data, which is then analyzed using its robust signal processing and statistical capabilities. Visualization tools in MATLAB aid in the interpretation of results, while ongoing optimization of test procedures and resource management ensure the tester's effectiveness. The final stage involves rigorous validation and verification to ensure the IC meets all specified performance and reliability standards. [11-15]

5. Result and Discussion

5.1. Results

The IC tester can effectively check the working of 74 series ICs, including ICs such as 7400, 7402, 7404, 7408, 7432, and 7486. The tester is able to quickly display the test results, indicating whether the tested IC is good or faulty. This makes the tester cost-effective, user-friendly, and reliable.

5.2. Discussion

The discussion delves into the comprehensive methodology used to create the IC tester, leveraging MATLAB's advantages in mathematical analysis, visualization, rapid prototyping, and hardware integration. However, the paper also acknowledges MATLAB's limitations, such as high licensing costs and resource-intensive nature. The future scope highlighted includes predictive maintenance, anomaly detection, automated test optimization, and integration with emerging technologies. Crucially, the project aimed to develop a low-cost testing platform to address the challenge faced by universities and small companies in affording expensive commercial testing equipment. The new approach allows for flexible and scalable testing of a wide range of circuit IPs, demonstrating the practical feasibility of the MATLAB-based tester. Overall, the results and discussions position the IC tester as a valuable tool for integrated circuit development and testing in both academic and industrial settings. Figure 2 shows IC Tester Using MATLAB and Figure 3 shows Output Screen.

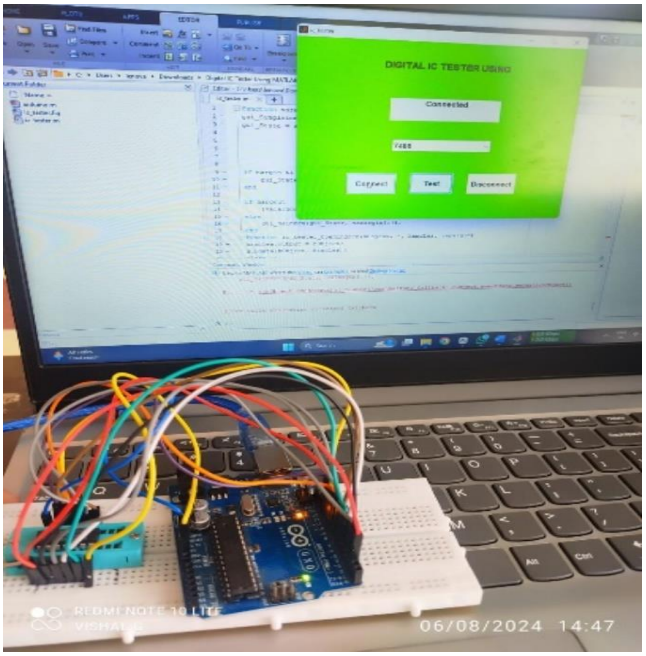

Figure 2 IC Tester Using MATLAB

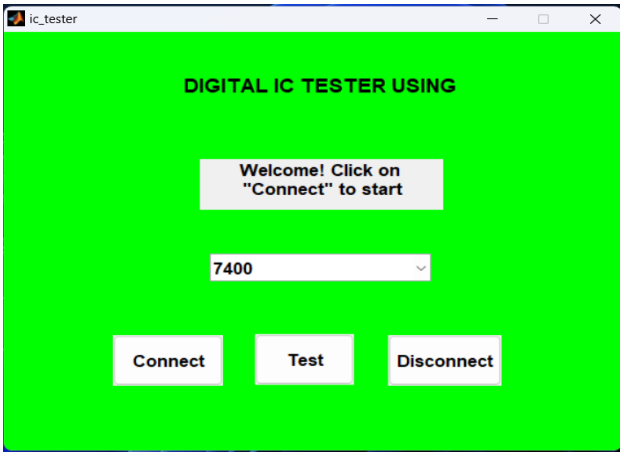

Figure 3 Output Screen

Conclusion

The MATLAB-based IC tester provides a cost-effective and reliable solution for testing the functionality and performance of integrated circuits,

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addressing the challenges faced by universities and small companies in affording specialized testing equipment. The paper outlines several future scope areas, such as integration with emerging technologies and advanced data analysis techniques, which can further enhance the capabilities of this MATLAB-powered IC testing platform.

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[3]. Mirza Shoaib Ahmed, Iqbal Muhammad Umair, Kashif Mehboob NED University of Engineering and Technology, Karachi.

[4]. Yasir Hashim, Marwa Awni, Abdullah Mufeed Computer Engineering Department, Faculty of Engineering, Tishk International University, Erbil, Iraq.

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